🕖 Luckí

## LUCKI CM ELECTRONICS Co.,Ltd



#### APPROVAL SHEET

Customer :	
Part Number:	2012 Seam Sealing Crystal
LK Part No.:	L216MK32M21L
Holder :	SMD2012
Frequency:	32.768KHz 12.5PF $\pm$ 20PPM
Manufacturer:	Lucki Electronics
Date:	2023-04-12

Prepared	Checked	Approved
Zhao Qian	Zhang Dongwei	Zhang Bin

#### (For Customer Use)

Acceptable	



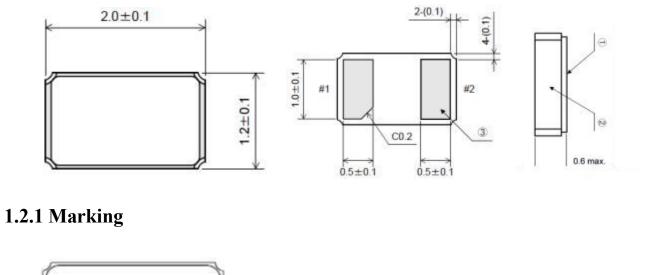
## 1. ELECTRICAL SPECIFICATIONS

#### 1.1 Hold Type: PSX-215

Parameter	Symb	Value	Condition
Frequency Range	Fo	32.768Khz	
Frequency Tolerance	∆f/fo	±20PPM	REF TO 25 ℃
Temperature Coefficient	К	$(-0.03\pm0.01) *10^{-6} / C^2$	
Turnover Temperature	Тто	25±5℃	
Operating Temperature Range	Тор	-40°C to 85°C	
Storage T m erature Range	Tst	-55°C to 125°C	
Quality Factor	Q	60,000 TYP	
Series Resistance	R <sub>1</sub>	90 KQ	KΩMax REF TO 25℃
Shunt Capacitance	Co	7PF or less	
Load Capacitance	CL	12.5 PF	
Insulator Resistance	IR	500 MQ	DC100V±15V
Drive Level	DL	<b>0.1</b> ц W	0.5 ц W Max
Capacitance Ratio	R	450 TYP	
Aging Rate	$\Delta$ /f	±3 PPM	at 25 °C ± 3 °C

# **ြ Luck၊** LUCKI CM ELECTRONICS Co.,Ltd

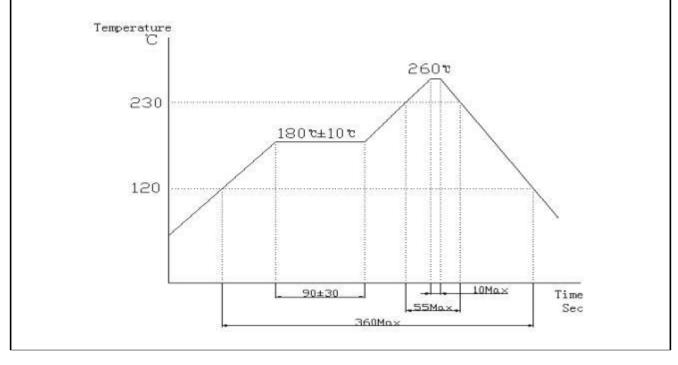




ROHS

32.768 KHz

#### 1.3 Reflow solder



# LUCKI CM ELECTRONICS Co.,Ltd



## 2. TEST STANDARD

#### 2.1 GENERAL ELECTRICAL CHARACTERISTICS AND VISUALTESTING

2.1.1 LOT CLASSIFICATION : If the quantity is 1000 PCS or more, 1000 PCS is one lot

2.1.2 SAMPLING TEST METHOD : MIL-STD- 105E G-II

2.1.3 TEST LEVEL

A) HIGH LEVEL DEFECT : AQL 0.065% [200 pcs]

B) MEDIUM LEVEL DEFECT : AQL 0.25% [50 pcs]

C) LOW LEVEL DEFECT :AQL 0.4% [32 pcs]

2.1.4 DEFECT CLASSIFICATION

A) HIGH LEVEL

@NO FREQUENCY

@MIXING

@LEAK DEFECT

B) MEDIUM LEVEL - ELECTRICAL CHARACTERISTIC DEFECT @FREQUENCY

@OSCILLATION

@ELECTRICAL CURRENT

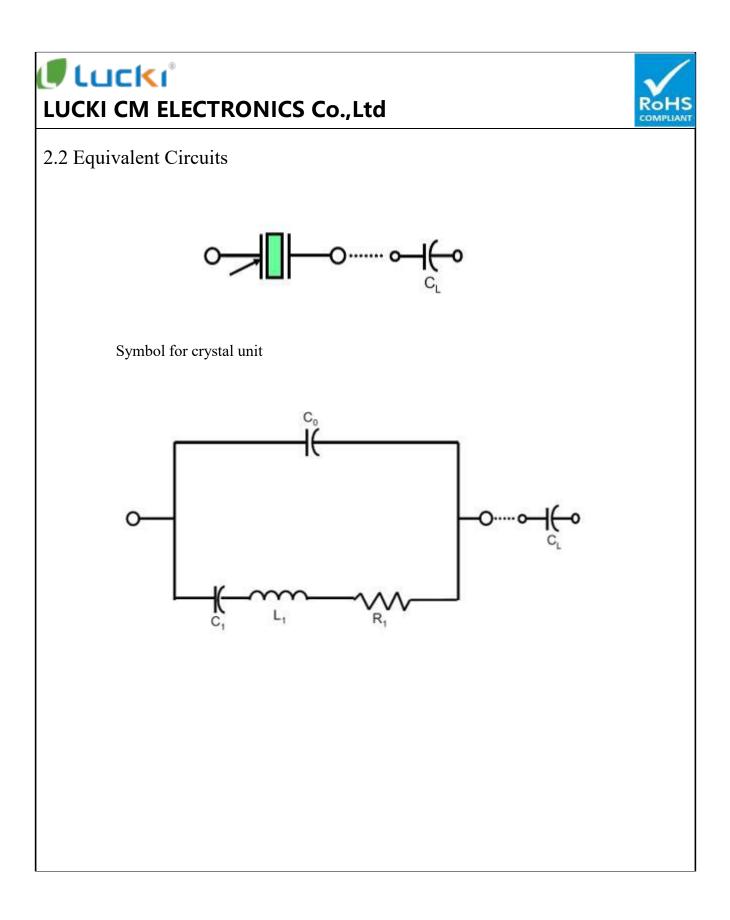
@OTHER ELECTRICAL CHARACTERISTICS DEFECT

C) VISUAL

@MARKING@WELDING@LEADS

@OTHER VISUAL DEFECT

#### TESTING METHOD AND ITS STANDARD CAN BE MODIFIED DEPENDING ON THE CUSTOMER'S REQUEST



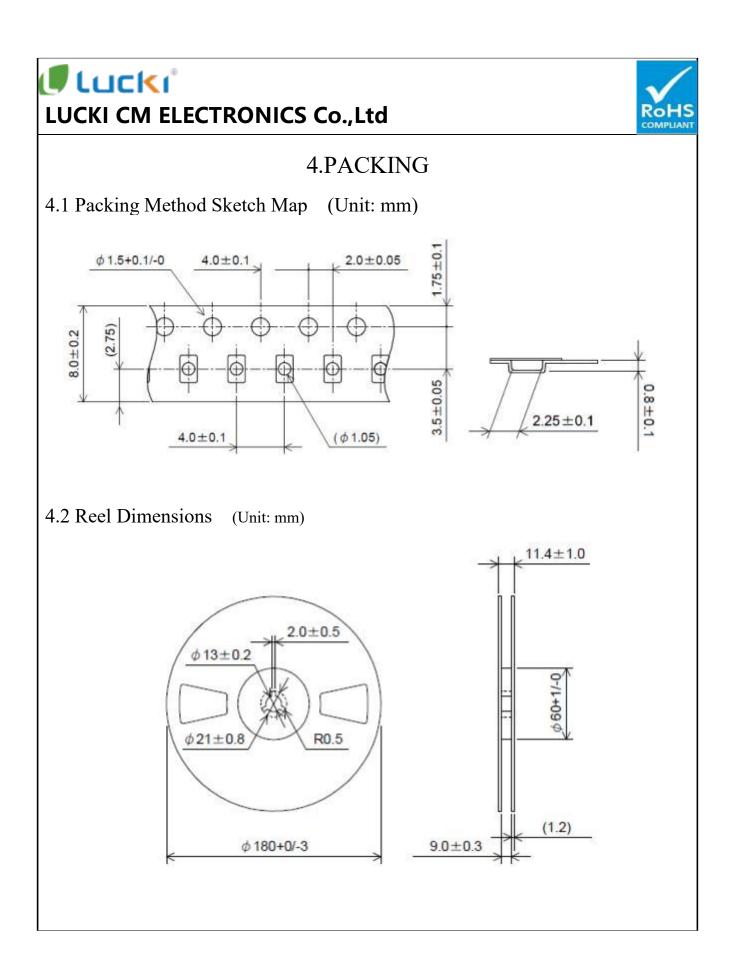


#### 3.RELIABILITY(MECHANICAL AND ENVIRONMENTAL ENDURANCE)

NO.	TEST	TEST METHOD AND CONDITION	REQUIREMENTS
1	VIBRATION	<ul> <li>(1)VIBRATION FREQUENCY: 10 TO 55HZ</li> <li>(2)VIBRATION AMPLITUDE: 1.5MM</li> <li>(3)CYCLE TIME: 1~2MIN(10-55-10HZ)</li> <li>(4)DIRECTION: X.Y.Z</li> <li>(5)DURATION: 2H/EACH DIRECTION</li> <li>(6)G-FORCE: ≥5G</li> </ul>	FREQUENCY CHANGE: ±10PPM MAX. RESISTANCE CHANGE: ±15%RRMAX
2	SHOCK	3 TIMES FREE DROP FROM 75CM HEIGHT TO HARD WOODEN BOARD OF THICKNESS MORE THAN 30MM.	FREQUENCY CHANGE: ±10PPM MAX. RESISTANCE CHANGE: ± 15%RRMAX.
3	LEAKAGE	PUT CRYSTAL UNITS INTO A HERMETIC CONTAINER AND HELIUM FOR 0.5-0.6. MPA,AND KEEP IT FOR 1H;CHECK THE LEAKAGE BY A HELIUM LEAK DETECTOR.	LEAKAGE:1X10 <sup></sup> 8MBAR.L/ MAX.
4	SOLDERABILIT Y	<ul> <li>(1)DIP THE LEADS INTO FLUX(ROJIN METHANOL) FOR 3~5S.</li> <li>(2)DIP THE LEADS INTO 245±5℃ 99% SN DIPPING SOLUTION FOR 5S.</li> </ul>	THE DIPPED PART OF THE LEADS SHOULD HAVE 95% SN COATING.
5	SOLDERI NG HEAT RESISISTANCE TEST	<ul> <li>(1)PERFORM ELECTRICAL CHARACTERISTICS TEST BEFORE STARTING THIS PROCEDURE.</li> <li>(2)DIP THE LEADS INTO FLUX(ROJIN METHANOL) 5±0.5S.</li> <li>(3)DIP THE LEADS INTO 260±5℃ 99% SN DIPPING SOLUTION FOR 5S.</li> <li>(4)TAKE THE UNIT OUT ,STORE AT ROOM TEMPER ATURE FOR 30S THEN MEASURE THE ELCTRICAL CHARACTERISTICS.</li> </ul>	SHOULD PASS SEALING AND VISUAL TEST. FREQUENCY CHANGE: ±10PPM MAX.
6	LEAK TEST	USE HELIUM LEAK DETECTOR. BOMBING PRESSURE: 5 KG/CM <sup>2</sup> BOMBING TIME: 2 HOURS LEAK SHOULD BE LESS THAN 1E-8 ATM.CC/SEC.	GAS OR AIR SHOULD NOT BE DETECTED.
7	HIGH TEMPERATURE ENDURANCE	THE CRYSTAL UNITS SHALL BE PUT IN SOMEWHERE FOR 500 HOURS AT TEMPERATURE OF 125℃±5℃, THEN KEEP IT FOR 1 TO 2 HOURS UNDER ROOM TEMPERATURE.	FREQUENCY CHANGE: ±10PPM MAX. RESISTANCE CHANGE: ± 15%RRMAX.



NO.	TEST	TEST METHOD AND CONDITION	REQUIREMENTS
8	LOW TEMPERATURE ENDURANCE	THE CRYSTAL UNITS SHALL BE PUT IN SOMEWHERE FOR 500 HOURS AT TEMPERATURE OF -40°C, THEN KEEP IT FOR 1 TO 2 HOURS UNDER ROOM.	FREQUENCY CHANGE: ±10PPM MAX. RESISTANCE CHANGE: ±15%RRMAX
9	HUMIDITY ENDURANCE	SOMEWHERE AT 40 °C±5 °C IN RELATIVE HUMIDITY OF 90%~95% FOR 72 HOURS, THEN KEEP IT FOR ONE OR TWO HOURS UNDER ROOM TEMPERATURE	FREQUENCY CHANGE: ±10PPM MAX. RESISTANCE CHANGE: ± 15%RRMAX.
10	TEMPERATURE CYCLE	TEMPERATURE SHIFT FROM LOW(-40 °C) TO HIGH(100 °C, KEEP 30 MINUTES), SATISFY HIGH(100 °C) TO LOW(-40 °C, KEEP 30 MINUTES), THEN GO UP TO ROOM TEMPERATURE FOR 10 CYCLES.	FREQUENCY CHANGE: ±10PPM MAX. RESISTANCE CHANGE: ± 15%RRMAX.
11	LEAD TENSILTY	<ul><li>(1)FIX THE UNIT.</li><li>(2)APPLY 2LB OF WEIGHT AXIS TO THE LESDS.</li><li>(3)TIME:5S</li></ul>	SHOULD PASS SEALING AND VISUAL TEST.
12	LEAD BENDING	<ol> <li>(1) ATTACH 1LB OF WEIGHT TO EACH OF THE LEADS.</li> <li>(2) BENDING ANGLE:90°(FROM THE NOMAL POSITION TO 45°OPPOSTTE DIRECTION)</li> <li>(3) BENDING TIME:3S(EACH DIRECTION) NUMBER OF BENDING:2TIMES</li> <li>(4) NUMBER OF BENDING:2TIMES</li> </ol>	SHOULD PASS SEALING AND VISUAL TEST.
13	MARKING ERASE	SUBMERGE THE UNIT INTO IPA[ISOPROPYL ALCOHOL] SOLUTION FOR 10MINUTES AND BRUSH THE MARKING 10 TIMES WITH A TOOTH BRUSH.	MARKING SHOULD NOT BE ERASED.



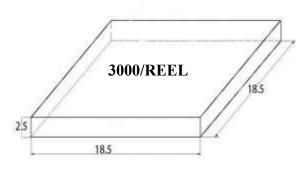


#### 4.3 Section of package

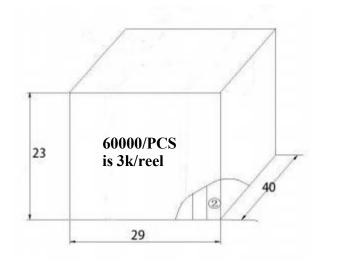
Package is made of corrugated paper with thickness of 0.8cm.Package has 10 inner boxes, each box has 1 reel 4.3.1 Quantity of package Per plastic reel 3000 pieces of Crystal Resonators

Per plastic reel 3000 pieces of Crystal Resonators Per inner box 3k/reel Per package 20 inner boxes & 10 inner boxes (30000 pieces of Crystal Resonators & 60000 pieces of Crystal Resonators)

4.3.2 Inner Box Dimensions (Unit: mm)



4.3.3 Dimensions and Mark (Unit: mm)





## 5. CAUTION

\* IN ORDER TO MAINTAIN QUALITY. WITHOUT CHANGE IN CHARACTERISTICS OF THECRYSTAL UNITS.PLEASE FOLLOW BELOW RECOMMENDATION

5.1 SHOCK

5.1.1 ALL CRYSTAL UNITS HAVE A THIN CRYSTAL BLANKS WITHIN IF IT IS DROPPED ABOVE THE ECOMMENDED DROPPING HEIGHT(500mm) THE SPECIFIC HARACTERISTICS AND APPEARANCE CAN BE CHANGED PLEASE PAY SPECIAL ATTENTION TO EXTERNAL SHOCK

5.2. ENVIRONMENTAL

5.2.1 CRYSTAL UNITS' FREQUENCY CAN BE CHANGED DUE TO SURROUNOING TEMPERATURE IF IT IS STORED NEXT TO A HIGH TEMPERATURE HETER (ABOVE+85'C) OR BELOW 40'C.AND A STRONG LIGHT SOURCE FOR LONG PERIOD OF TIME. THE ELECTRICAL CHARACTERISTICS CAN BE CHANGED IT IS SUGGESTED THAT THESE ENVIROMENTS BE AVOIDED

5.2.2 IF THE UNIT IS PLACED IN A HUMID ENVIRONMENT. LEAD TERMINAL CAN BE DAMAGED: THEREFORE.DO NOT STORE THE CRYSTAL UNITS IN A HUMID ENVIRONMENT

5.2.3 CRYSTALUNIT HAS VIBRATING CHARACTERISTICS IF IT IS PLACED WHERE VIBRATION EXISTS THE OPERATING CHARACTERISTICS CAN BE ALTERED; THEREFORE THIS ENVIRONMENT SHOULD BE AVOIDED

5.3 LEADS

5.3.1 AFTER SOLDERING CRYSTAL UNITS INTO A PCB IMPACTING THE UNIT FROM THETOP,BOTTOM LEFT OR RIGHT SIDE OF THE UNIT CAN SHATTER THE GLASS PORTION OF THE BASE AENDERING THE UNIT USELESS

5.4 ASSEMBLY METHOD

5.4.1 CORRECT ULTRASONIC FREQUENCY FOR CLEANING SHOULD BE LESS THAN 20KHZ

5.4.2 SOLDERING SHOULD BE BONE USING IEC 61760- 1 OR PB-Free Products 5.5 STORAGE

5.5.1 IF THE CRYSTAL UNITS ARE STORED IN HUMID OR SALTY ENVIRONMENT APPEARANCE CAN BE CHANGED AND SOLDERABILITY CAN DETERIORATE; THEREFORE AOID STORING IN SUCH ENVIRONMENT DO NOT STORE THE CRYSTAL UNIT MORE THAN 3 MONTHS



## 6. Pb-Free PRODUCTS

LK Pb-free program.

The LK Pb-free program is implemented in accordance with European Union (EU)

Legislation titled "Restriction of the use of certain Hazardous Substances

(RoHS)" including banning the use of Pb in electronic assemblies after July 1, 2006.

LK Definitions

Pb-Free Classification: Component and Assembly Pb content shall be less than 0. 1% by weight of the device (in accordance to IPC/EIA J-STD-006) and shall not be intentionally introduced .

Components: LK's definition of components apply to quartz crystal devices

Assemblies: LK's definition of assemblies apply to oscillator devices (XO,

VCXO and TCXO's)

Recommended Solder Composition

LK's is following industry trend of using alloy range

Sn-Ag(3.4-4. 1)-Cu(0.45-0.9) for reflow and wave soldering.

Pb-free Part Number Identification:

When applicable, the LK specification sheet shall indicate if the device is classified as Pb-free.

Marking and Labeling: LK has a Pb-free labeling method for the packaging of all Pb

-free products. The lowest level shipping container shall identify the products as

Pb-free.

#### OTHERS

If you have some doubt or unknowing about this specification, Please contact us for Settlement or development.

### **X-ON Electronics**

Largest Supplier of Electrical and Electronic Components

Click to view similar products for Crystals category:

Click to view products by Lucki manufacturer:

Other Similar products are found below :

CX3225GB25000M0PPSZ1 718-13.2-1 7A-40.000MAAE-T FL200085 99-BU 9B-15.360MBBK-B 9C-7.680MBBK-T H10S-12.000-18-EXT-TR ABC2-6.000MHZ-D4Z-T ABLS-20.000MHZ-D2-T ABS071-32.768KHZ-6-T R38-32.768-12.5-5PPM-NPB 21U15A-21.4MHZ RTX-781DF1-S-20.950 LFXTAL066198Cutt 9C-14.31818MBBK-T A-11.000MHZ-27 ABL-27.000MHZ-B4Y-T ABM11-132-24.000MHZ-T3 ABM3B1-25.000MHZ-D2Y-T SPT2A-.032768B SPT2A.032768G SSPT7F-9PF20-R LFXTAL065253Cutt LFXTAL066431Cutt XT9S20ANA14M7456 XT9SNLANA16M 7A-24.576MBBK-T 7B-30.000MBBK-T CX2520DB16000H0HPQCC MMCC2R32.7680KHZ 6504-202-1501 6526-202-1501 ABLS-12.000MHZ-B2Y-T 7A-10.000MBBK-T SG636PCE-20.000MC 3404 CM315D32768EZFT C1E-24.000-7-2020-R C1E-19.200-12-1530-X-R C1E-16.000-12-1530-X-R ABM11-16.000MHZ-9-B1U-T FL5000014 EUCA18-3.1872M FX0800015 425F35E027M0000 FP0800018 MS3V-T1R-32.768kHz-7pF-20PPM-TA-QC-Au VXM7-1C1-16M000 MS3V-T1R-32.768kHz-9pF-20PPM-TA-QC-Au